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Complete if Known Substitute for form 1449/PTO Application Number 10/530,242-Conf. #9928 INFORMATION DISCLOSURE Filing Date June 6, 2005 STATEMENT BY APPLICANT First Named Inventor Jochen Baurmeister #nU hA 1745 (Use as many sheets as necessary) Not Yet Assigned Examiner Name Sheet 1 1 15588-00010-US Attorney Docket Number

U.S. PATENT DOCUMENTS									
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear				
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Signatu	re	Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. *CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if ⁶ Applicant in the conformance and not considered. The conformance with MPEP 609. Draw line through citation if not in conformance and not considered. The conformance with MPEP 609. Draw line through citation if not in conformance and not considered. The conformance with MPEP 609. Draw line through citation if not in conformance and not considered. The conformance with MPEP 609. Draw line through citation in conformance with MPEP 609. Draw line through citation in conformance and not considered. The conformance with MPEP 609. Draw line through citation in conformance and not considered. The conformance with MPEP 609. Draw line through citation in conformance and not considered. The conformance with MPEP 609. Draw line through citation in conformance and not considered with an expensive property of the conformance and not considered with an expensive property of the conformance with the conformance and not considered with the conformance and not considered with the conformance with the conformance and not considered with the conformance with the con possible. 6 Applicant is to place a check mark here if English language Translation is attached.